# EAST Search History

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|---|---|---|---|---|---|---|
| L3 | 554 | semiconductor same test adj pads and chip | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2006/11/17 15:16 |
| L4 | 2 | "2002-151644" | JPO; DERWENT | OR | OFF | 2006/11/17 15:17 |
| L5 | 2 | jp-2002151644-$.did. | JPO; DERWENT | OR | OFF | 2006/11/17 15:17 |